

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re: Wenbing Yun *et al.* Confirmation No: 7844  
Application No: 10/683,872 Group: 2872  
Filed: October 10, 2003 Examiner: Assaf, Fayez G.  
For: Short Wavelength Metrology  
Imaging System  
Customer No.: 29127

Attorney Docket No.	0002.0004.us
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**AMENDMENT UNDER RULE 312**

**Commissioner for Patents**  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

In response to the Notice of Allowability mailed June 19, 2007 (Paper No. 20070609), please amend the above-captioned patent application as follows:

-amendments to the claims are reflected in the listing of claims in the Listing of Claims section;

Finally, reconsideration is requested in view of the remarks set forth in the Remarks section.